



PATENT APPLICATION

IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Iori YOSHIKAWA

Group Art Unit: 2877

Application No.: 10/589,336

Filed: August 14, 2006

Docket No.: 127630

For: MEASUREMENT METHOD, TRANSFER CHARACTERISTIC MEASUREMENT METHOD, ADJUSTMENT METHOD OF EXPOSURE APPARATUS, AND DEVICE MANUFACTURING METHOD

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to Reference 1 of the PTO Form 1449 filed concurrently with the Information Disclosure Statement on October 17, 2006. It is respectfully requested that this be corrected to include the English-language translation with the English-language abstract, which provides further concise explanation of potential relevance of the reference cited therein.

This Information Disclosure Statement is being before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.

Respectfully submitted,

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MAC:SPC/ejw

Date: November 22, 2006

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DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461
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Sheet 1 of 1Form PTO-1449
(REV. 1/06)US Dept. of Commerce
PATENT & TRADEMARK OFFICEATTY DOCKET NO.
127630APPLICATION NO.
10/589,336

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANT(S)
Iori YOSHIKAWAFILING DATE
August 14, 2006GROUP
2877

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name

FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
	1	JP A 04-132909	05/07/1992	JAPAN	X	X

OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER

DATE CONSIDERED

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: November 22, 2006